## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | MIERNIK ET AL. | Examiner | Art Unit | Duc Nguyen | 2643 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-			
	В	US-			
	С	US-			
	D	US-	2		
ن- ن	E	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	κ	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP02000209298	07-2000	Japan	Marinho et al	
	0					
	Р					
	α					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

	TOTAL POOR LINE						
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
	U						
	٧						
	w						
	x						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.